

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10792322	LEE ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Liu, Li	2613

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
398	19-34, 66-79	11/29-12/05, 2006	LL
385	24-27	11/29-12/05, 2006	LL
359	124-135	11/29-12/05, 2006	LL

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
EAST: US-PGPUB, USPAT, JPO, EPO, DERWENT, IBM_TDB	11/29-12/05, 2006, 5/17/2007	LL
IEEE	11/29/2006	LL
GOOGLE	11/29/2006	LL
PLUS	5/17/2007	LL

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>